

NEC00P063-To

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Kazuki Yokota

Serial No.: Not Yet Assigned

Group Art Unit: Not Yet Assigned

Filing Date: Concurrently Herewith

Examiner: Unknown

For: OVERLAY MARK, METHOD OF MEASURING OVERLAY ACCURACY,
METHOD OF MAKING ALIGNMENT AND SEMICONDUCTOR DEVICE
THEREWITH

Assistant Commissioner of Patents
Washington, D.C. 20231

PRELIMINARY AMENDMENT

Sir:

Prior to examination on the merits and calculation of the filing fee, please amend the
above-identified application as follows:

IN THE SPECIFICATION:

~~Page 10, line 14, delete "Fig. 1 is" and insert --Figs. 1(a) and 1(b) are--.~~

~~line 17, delete "Fig. 2 is" and insert --Figs. 2(a) and 2(b) are--.~~

~~line 20, delete "Fig. 3 is" and insert --Figs. 3(a) and 3(b) are--.~~

~~line 23, delete "Fig. 4 is" and insert --Figs. 4(a) and 4(b) are--.~~

~~line 26, delete "Fig. 5 is" and insert --Figs. 5(a) and 5(b) are--.~~

~~Page 11, line 2, delete "Fig. 6 is" and insert --Figs. 6(a) and 6(b) are--.~~

~~line 20, delete "Fig. 12 is" and insert --Figs. 12(a) and 12(b) are--.~~

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